

**Problem 17.1**

Regenerate Table 17.1. If the water level where a cup of water is removed is 4.7 instead of 5. How are the results affected? If the sensing time is increased how are the final results affected (compare a water level of 5 against 4.7).

In table 17.1, if the water level to remove a cup of water is 4.7 instead of 5, the results are not affected. This is shown in the table below.

Time (sec)	Water level in sigma buckets(cup)	Remove cup?	Running average
0	4.7	no	0
10	4.95	<b>yes</b>	1
20	4.2	no	0.5
30	4.45	no	0.33
40	4.7	no	0.25
50	4.95	<b>yes</b>	0.4
60	4.2	no	0.33
70	4.45	no	0.29
80	4.7	no	0.25
90	4.95	<b>yes</b>	0.33
100	4.2	no	0.3
110	4.45	no	0.27
120	4.7	no	0.25
130	4.95	<b>yes</b>	0.3
140	4.2	no	0.29
150	4.45	no	0.26
160	4.7	no	0.25
170	4.95	<b>yes</b>	0.29

In the following table, the sensing time increases to 370 sec. The final results compare both water level 5 and 4.7. From the table we can see, the longer we sense the closer our output moves to 0.25 cup/10 seconds. And, if there is any error, it will average out over time.

Water level =4.7 cup:

Water level =5 cup:

Time (sec)	Water level in sigma buckets(cup)	Remove cup?	Running average		Water level in sigma buckets(cup)	remove cup?	Running average
0	4.7	no	0		5	no	0
10	4.95	<b>yes</b>	1		5.25	<b>yes</b>	1
20	4.2	no	0.5		4.5	no	0.5
30	4.45	no	0.33		4.75	no	0.33
40	4.7	no	0.25		5	no	0.25
50	4.95	<b>yes</b>	0.4		5.25	<b>yes</b>	0.4
60	4.2	no	0.33		4.5	no	0.33
70	4.45	no	0.29		4.75	no	0.29
80	4.7	no	0.25		5	no	0.25
90	4.95	<b>yes</b>	0.33		5.25	<b>yes</b>	0.33
100	4.2	no	0.3		4.5	no	0.3
110	4.45	no	0.27		4.75	no	0.27
120	4.7	no	0.25		5	no	0.25
130	4.95	<b>yes</b>	0.3		5.25	<b>yes</b>	0.3
140	4.2	no	0.29		4.5	no	0.29
150	4.45	no	0.26		4.75	no	0.26
160	4.7	no	0.25		5	no	0.25
170	4.95	<b>yes</b>	0.29		5.25	<b>yes</b>	0.29
180	4.2	no	0.28		4.5	no	0.28
190	4.45	no	0.26		4.75	no	0.26
200	4.7	no	0.25		5	no	0.25
210	4.95	<b>yes</b>	0.29		5.25	<b>yes</b>	0.29
220	4.2	no	0.27		4.5	no	0.27
230	4.45	no	0.26		4.75	no	0.26
240	4.7	no	0.25		5	no	0.25
250	4.95	<b>yes</b>	0.28		5.25	<b>yes</b>	0.28
260	4.2	no	0.27		4.5	no	0.27
270	4.45	no	0.26		4.75	no	0.26
280	4.7	no	0.25		5	no	0.25
290	4.95	<b>yes</b>	0.28		5.25	<b>yes</b>	0.28
300	4.2	no	0.27		4.5	no	0.27
310	4.45	no	0.26		4.75	no	0.26
320	4.7	no	0.25		5	no	0.25
330	4.95	<b>yes</b>	0.27		5.25	<b>yes</b>	0.27
340	4.2	no	0.26		4.5	no	0.26
350	4.45	no	0.26		4.75	no	0.26
360	4.7	no	0.25		5	no	0.25
370	4.95	<b>yes</b>	0.27		5.25	<b>yes</b>	0.27

## Problem 17.2

time, seconds	water level in the sigma bucket (cups)	add cup? (water level > 5?)	Running average
0	5	no	0
10	4.7	yes	0.5
20	5.4	no	0.33
30	5.1	no	0.25
40	4.8	yes	0.4
50	5.5	no	0.33
60	5.2	no	0.29
70	4.9	yes	0.38
80	5.6	no	0.33
90	5.3	no	0.3
100	5	no	0.27
110	4.7	yes	0.33
120	5.4	no	0.31
130	5.1	no	0.29
140	4.8	yes	0.33
150	5.5	no	0.31
160	5.2	no	0.29
170	4.9	yes	0.33

*note: assume 5 cups initially; 0.3 cups leaves every 10 seconds*

### P17.3

Referring to figure 17.6, with  $I_{cup}$  replaced with a resistor  $R_{cup}$ , and assuming that the clock frequency is large, ( this is required so that  $\Delta V_{bit}$  is small, which simplifies the equations.) Equations 17.3 through 17.8 are derived below,

$$\text{With, } I_{cup} = I_R = \frac{VDD - V_{bit}}{R_{cup}}$$

$$\frac{I_{bit}}{C_{bit}} = \frac{\Delta V_{bit}}{T} \quad (17.3)$$

$$Q_{bit} = I_{bit} * T = C_{bit} * \Delta V_{bit} \quad (17.4)$$

$$Q_{cup} = \frac{VDD - V_{bit}}{R_{cup}} * \frac{M}{N} * T \quad (17.5)$$

$$Q_{bit} = I_{bit} * T = Q_{cup} = \frac{VDD - V_{bit}}{R_{cup}} * \frac{M}{N} * T \quad (17.6)$$

$$I_{bit} * \frac{R_{cup}}{VDD - V_{bit}} = \frac{M}{N} \quad (17.7)$$

$$\Delta V_{bit, \max} = \frac{VDD - V_{bit}}{R_{cup}} * \frac{T}{C_{bit}} \quad (17.8)$$

The current through the resistor must be larger than the  $I_{bit}$ . If it is not, the current through the resistor will not be able to keep  $I_{bit}$  fed, and  $V_{bit}$  will go to zero.

**Prob 17-4:** Demonstrate, using SPICE simulations, that the error because of parasitics, as seen in fig 17.7, is reduced by connecting the switch to a 1v source instead of ground.

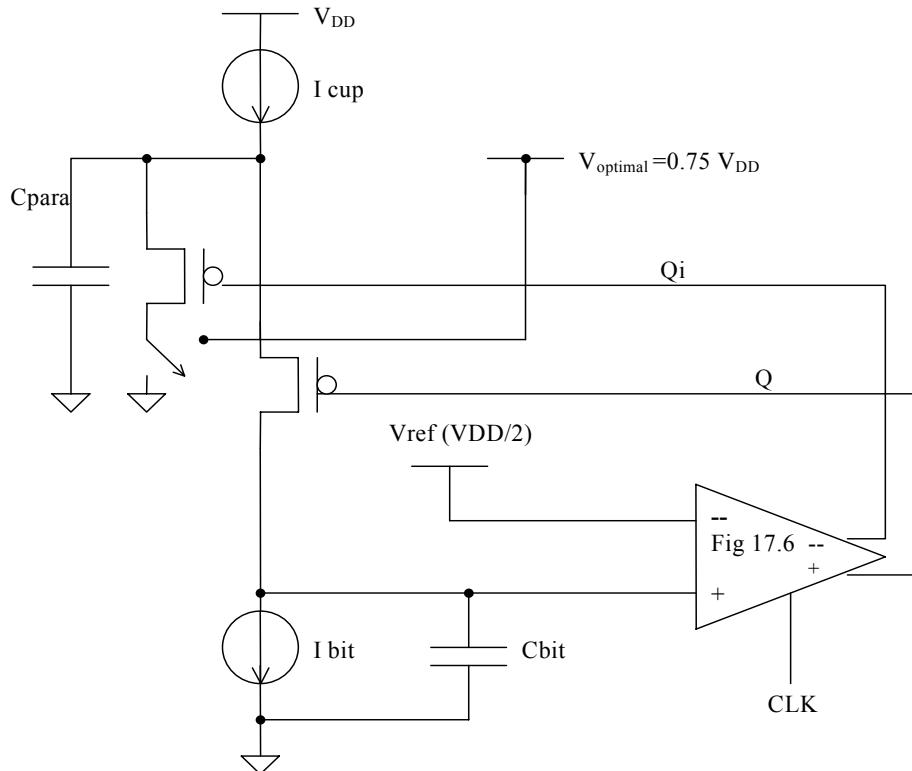
[Ans]:

Based on Fig 17-4-1 and Fig 17-4-2, we can analyze the current source parasitic capacitance effects on DSM sensing precision. SPICE simulation results are shown as Fig 17-4-4, Fig17-4-5, and Fig17-4-6; summarized as Table 17-4-3.

By interpolating the simulation results, we can make the following conclusions:

- (1). Sensing Error because of parasitics, as seen in fig 17.7, is reduced by connecting the switch to a VDD source instead of ground.
- (2). Sensing Error due to  $C_{\text{parasitics}}$  can be eliminated by choosing the proper voltage source connected to  $C_{\text{par}}$  during transition in order to compensate the charge sharing between  $C_{\text{par}}$  and  $C_{\text{bit}}$ . As indicated in Fig 17-4-6, I would recommend  $0.75V_{\text{DD}}$  instead of  $V_{\text{DD}}$ .
- (3). Current noise through  $C_{\text{parasitics}}$  is also a good indication of charge sharing or injection; we will mainly care about at NO-to-YES transitions.

Fig 17-4-1 Analysis of Current source parasitic Capacitance Effect



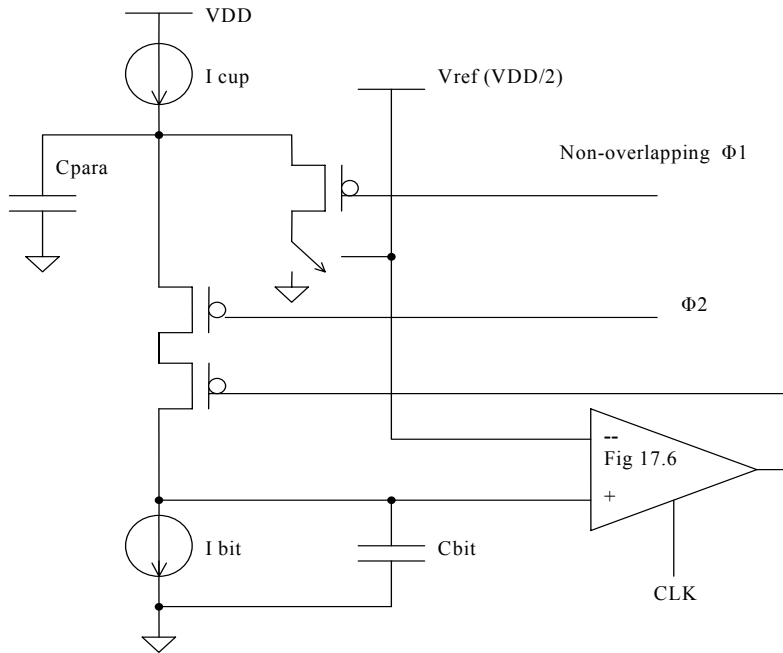


Fig 17-4-2 Alternative design of Current source parasitic Capacitance Effect

Table 17-4-3 SPICE Simulation results of parasitic Capacitance effects

	$C_{par}$ to GND	$C_{par}$ to Vref	$C_{par}$ to VDD	
$I_{sense}$ (uA)	2.8	2.5	1.6	
$I_{actual}$ (uA)	2	2	2	
Error (%)	40%	25%	-20%	

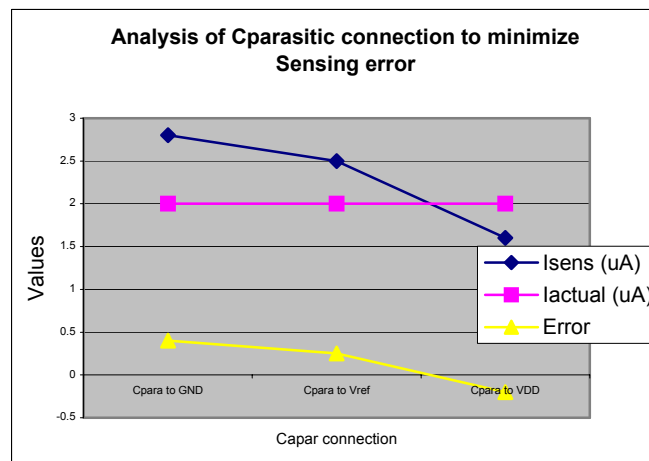


Fig 17-4-4 SPICE Simulation parasitic Capacitance (connect GND-Top /VDD-Bottom)

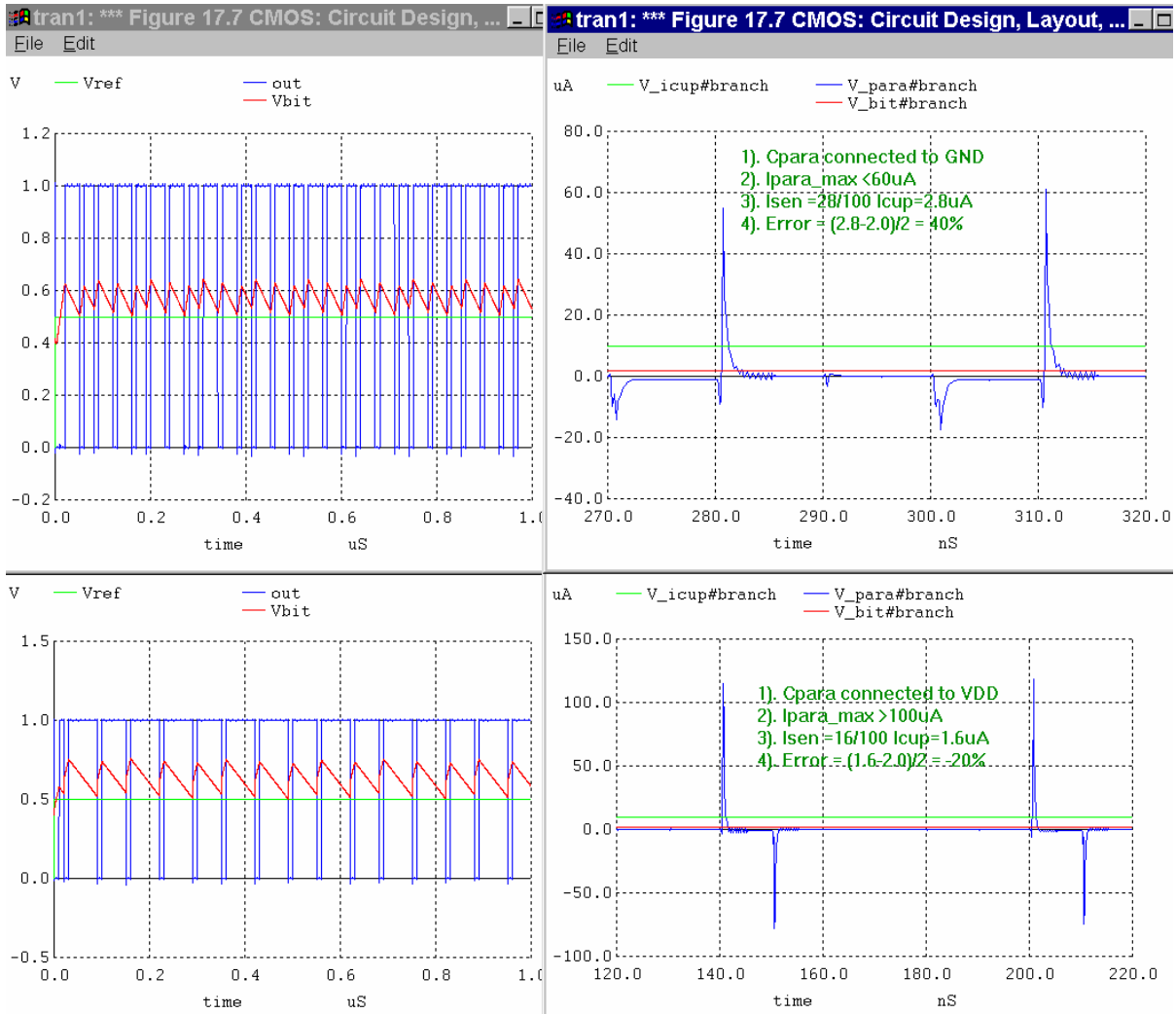


Fig 17-4-5 SPICE Simulation parasitic Capacitance (connect Vref = VDD/2)

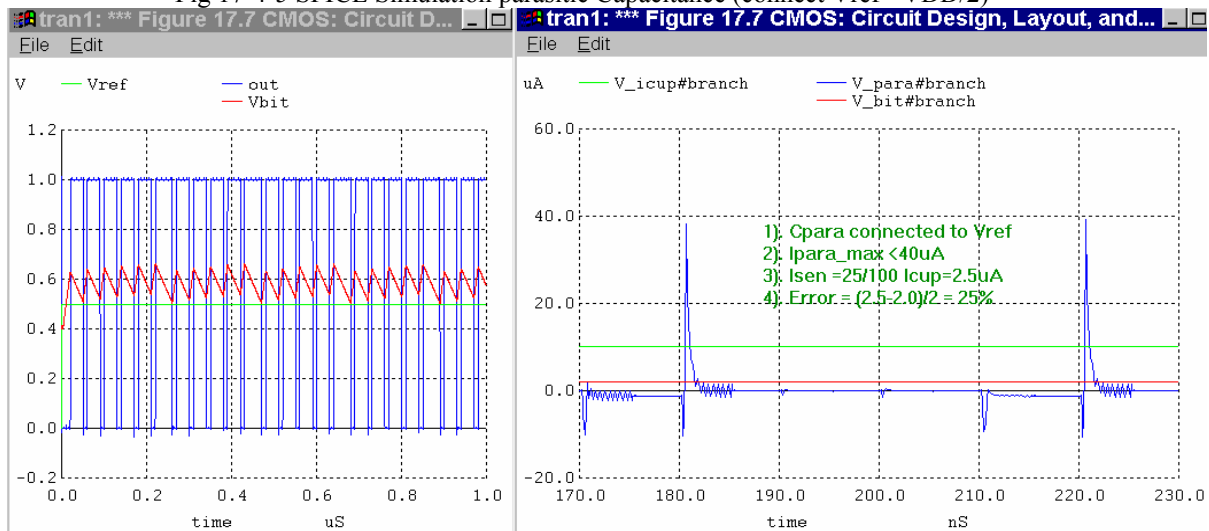
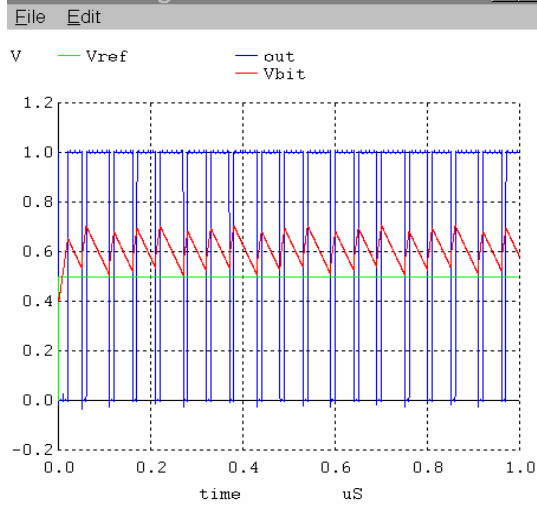
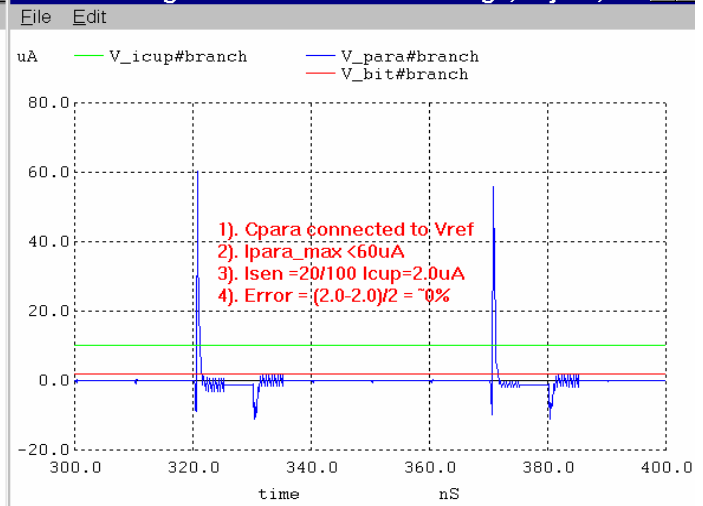


Fig 17-4-6 SPICE Simulation parasitic Capacitance (connect {Vref + VDD}/2 = 0.75VDD) to eliminate sensing error caused by Cpara from current source

tran1: \*\*\* Figure 17.7 CMOS: Circuit Des...



tran1: \*\*\* Figure 17.7 CMOS: Circuit Design, Layout, a...



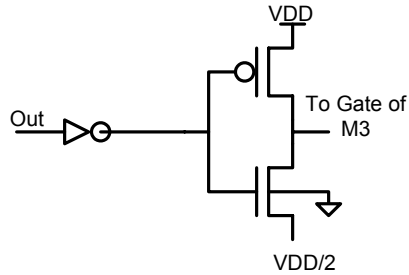


**Problem 17.5****Tris Tanadi (ttanadi@hotmail.com)**

Showing, using simulations, that if the output of the comparator swings from VDD to VDD/2 we can eliminate M4 in Fig. 17.9 and still have  $Q_{cup} = C_{cup} * (VDD - V_{REF} - V_{THP})$ . Why? Does the amount of current supply by VDD/2 increase? Could this be a problem?

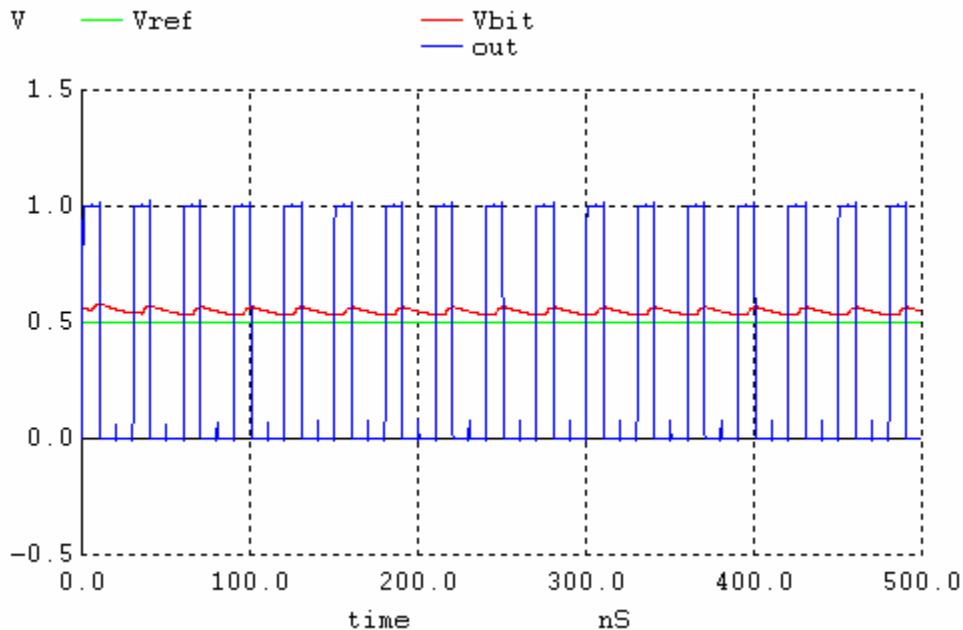
**Answer:**

We will compare the operation of circuit from Fig. 17.18 with similar circuit but without M4 plus with the following extra circuit.

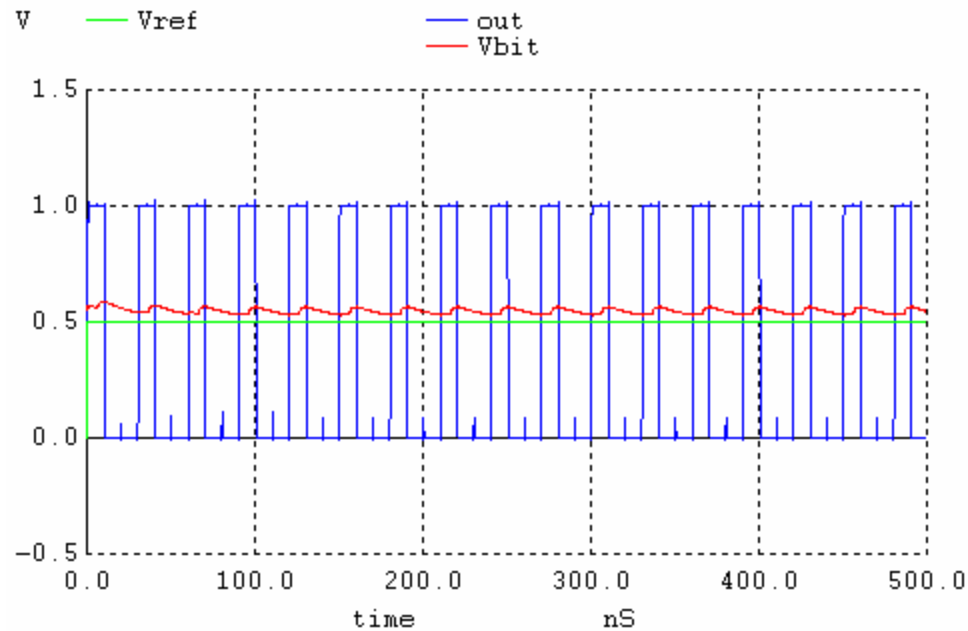


Yes, we will still have  $Q_{cup} = C_{cup} * (VDD - V_{REF} - V_{THP})$  because when output of the comparator is low we will dump the charge from  $C_{cup}$  to the bit line. Since the logic low of the comparator is VDD/2 which is equal to VREF then the equation still valid. The next two plots are comparing the result using Fig. 17.18 and the new circuit. The Vbit using both circuits are similar. This means that Qcup between two circuits are the same too.

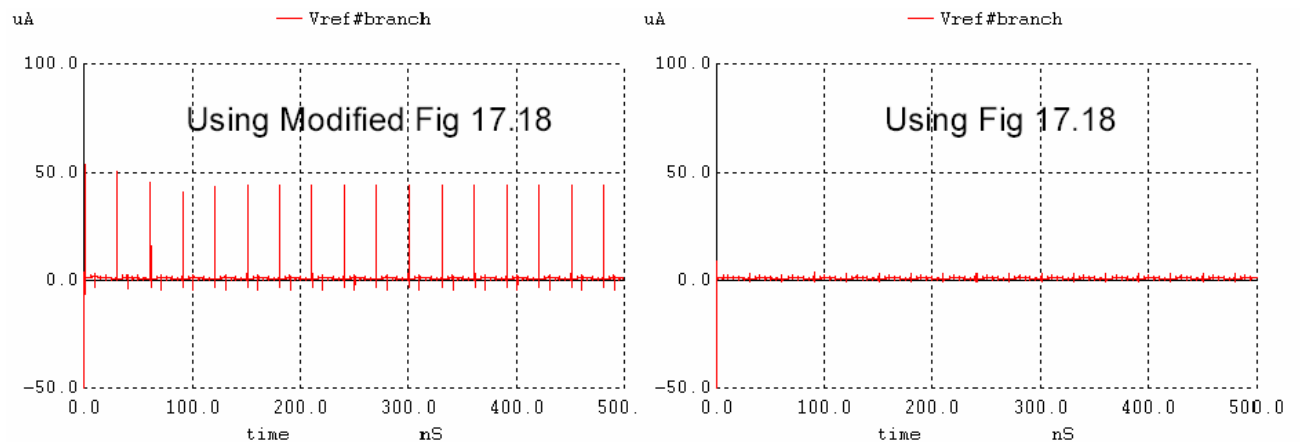
Using Fig 17.18



Using new circuit.



Using the modified Fig 17.19, we will burn more current through VREF because of the extra inverter to change the swing of the comparator output will draw current whenever the output is switched LOW.



The problems of using this circuit are the current increase from VREF and also the extra are required for the extra inverters.

The SPICE source code for the modified circuit:

\*\*\* Problem 17.5 \*\*\*

```
.control
destroy all
run
let out=Qi
plot Vbit Vref out
```

```
plot Vref#branch ylimit -10u 100u
.endc
```

```
.option scale=50n
.ic V(vbit)=550m
.tran .25n 500n 0 .25n UIC
```

VDD	VDD	0	DC	1	
Vphi1	phi1	0	DC	0	PULSE 1 0 1n 0 0 4n 10n
Vphi2	phi2	0	DC	0	PULSE 1 0 6n 0 0 4n 10n
Vclock	clock	0	DC	0	PULSE 0 1 0 0 0 5n 10n
Vref	Vref	0	DC	0.5	

M1	Vd1	phi1	VDD	VDD	PMOS L=1 W=20
M2	Vd2	phi2	Vd1	VDD	PMOS L=1 W=20
M3	Vbit	vx	Vd2	VDD	PMOS L=1 W=20
Ccup	Vd1	0	100f		

Cbit	Vbit	0	500f
Rmbit	Vbit	Vref	50k

\* The extra circuit from Fig. 17.18

X2 Q	Qbar	VDD Inv			
M4	vx	Qbar	Vref	0	NMOS L=1 W=10
M5	vx	Qbar	VDD	VDD	PMOS L=1 W=20

X1	VDD	Vbit	Vref	clock	Qi	Q	Comp
.subckt Comp							
M1	d1	Outp	db1	0	clock	Qi	Q
M2	d2	Outm	db2	0			
M3	Outm	Outp	VDD	VDD			
M4	Outp	Outm	VDD	VDD			
MS1	Outm	clock	d1	0			
MS2	Outp	clock	d2	0			
MS3	Outm	clock	VDD	VDD			
MS4	OUtp	clock	VDD	VDD			
MB1	db1	Inp	0	0			
MB2	db2	Inm	0	0			
X1	Outp	Q	Qi	VDD	Nand		
X2	Qi	Outm	Q	VDD	Nand		

```
.ends
```

.subckt Nand A B ANANDB VDD					
M1	ANANDB A	d2	0		NMOS L=1 W=10
M2	d2	B	0	0	NMOS L=1 W=10
M3	ANANDB A		VDD	VDD	PMOS L=1 W=20
M4	ANANDB B		VDD	VDD	PMOS L=1 W=20

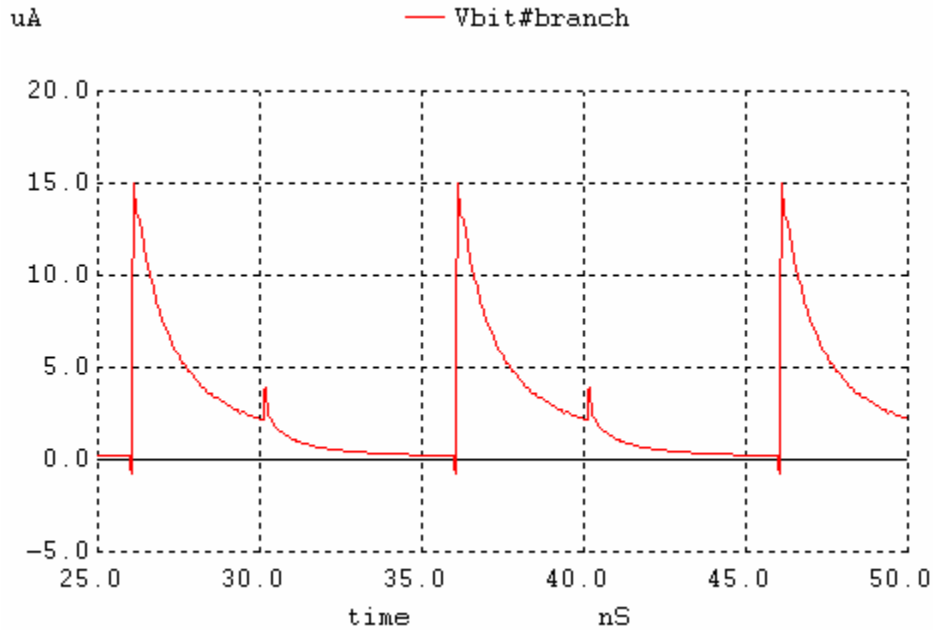
```
.ends
```

.subckt Inv In Out VDD					
M1	out	In	0	0	NMOS L=1 W=10
M2	out	In	VDD	VDD	PMOS L=1 W=20

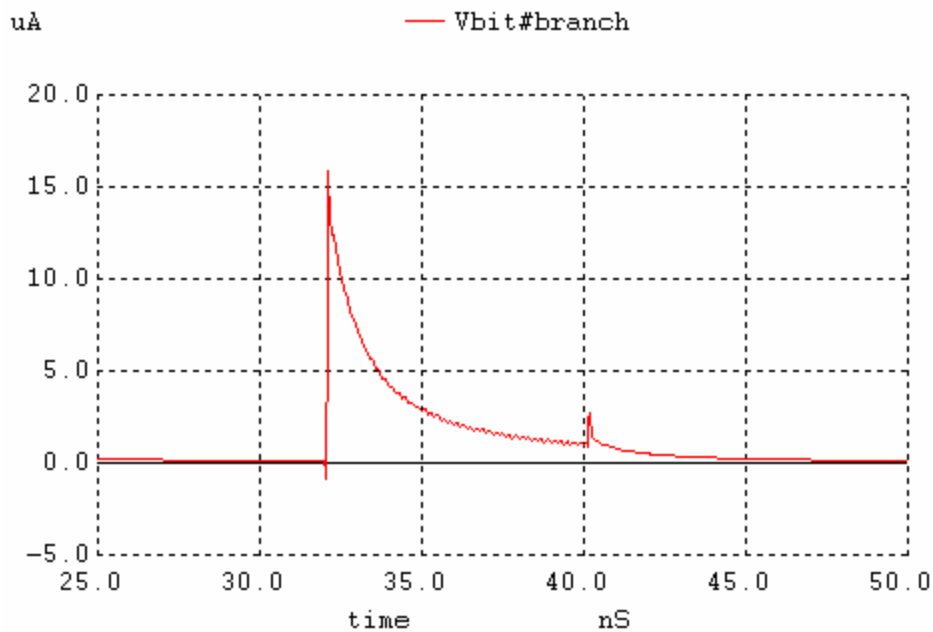
```
.ends
```

17.6 By reducing the clock frequency, C<sub>cup</sub> will be discharged more so the incomplete settling will be more complete. From the simulation results below, when phi2 shut off, C<sub>cup</sub> has dumped more charge onto the bit line at lower clock frequency and a wider M4.

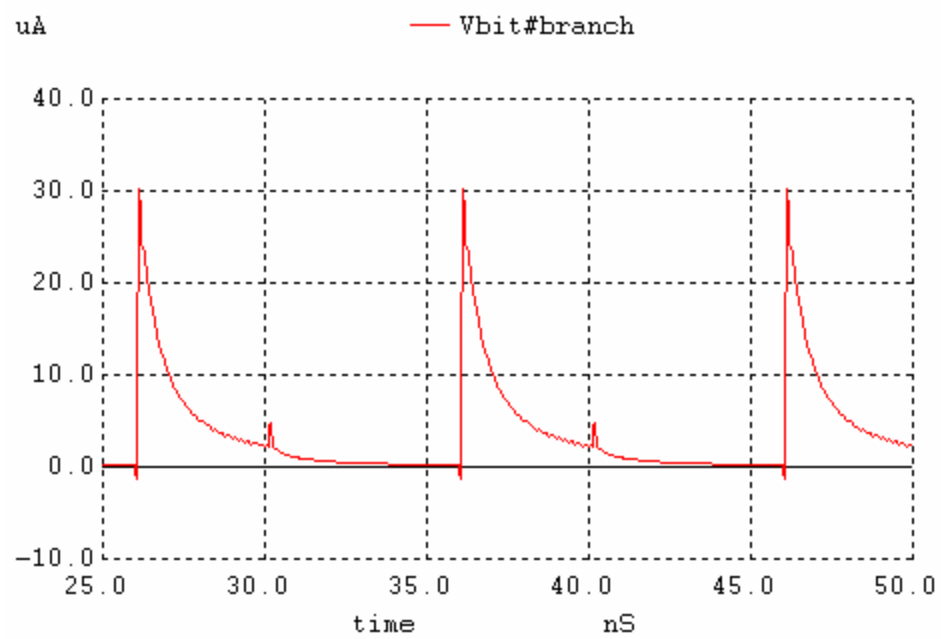
Clock is at 10ns, phi2 low time is at 4 ns and M4 is 40 wide:



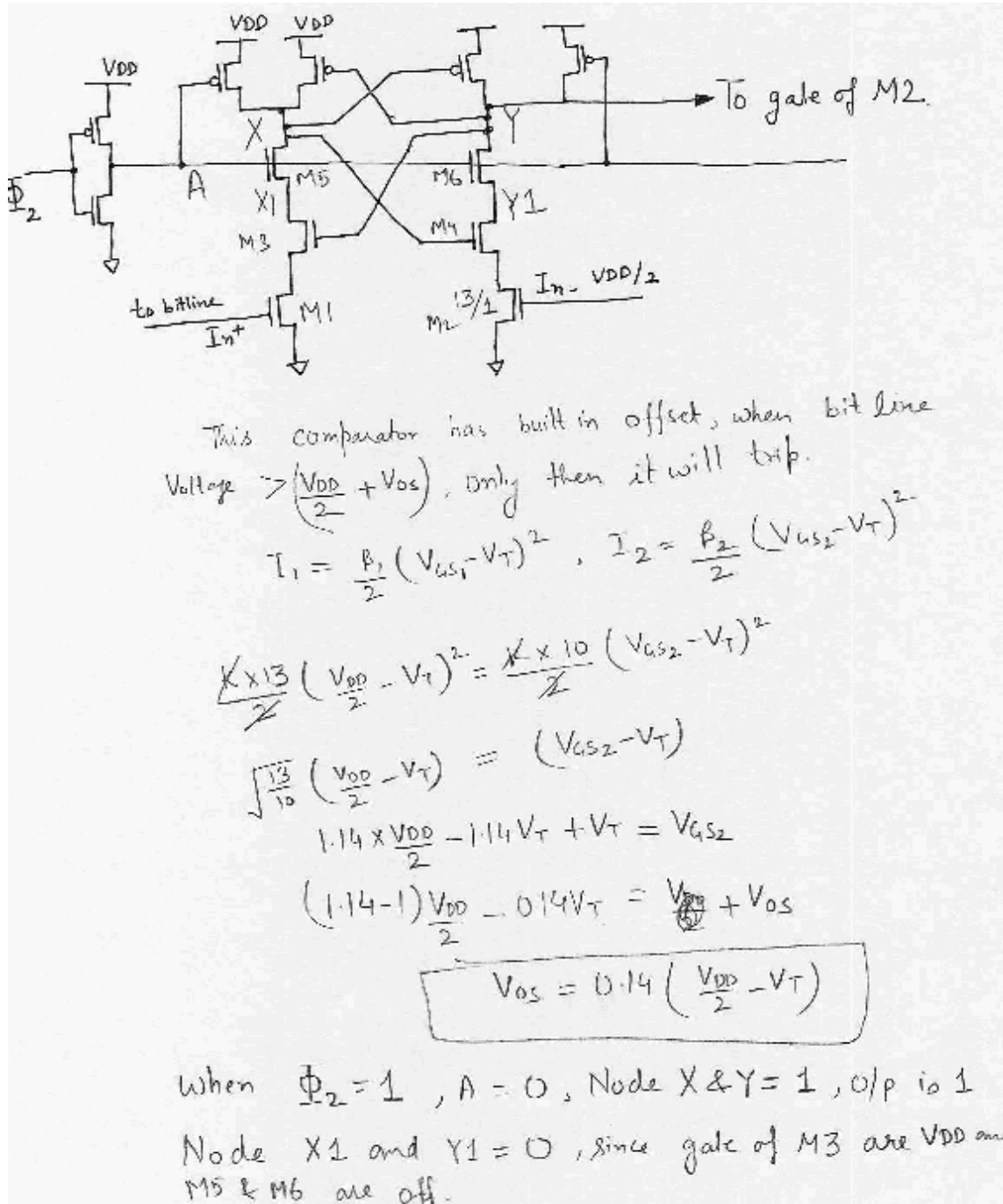
Clock is at 10ns, phi2 low time is at 4 ns:



M4 with width 100.



# Problem 17.7



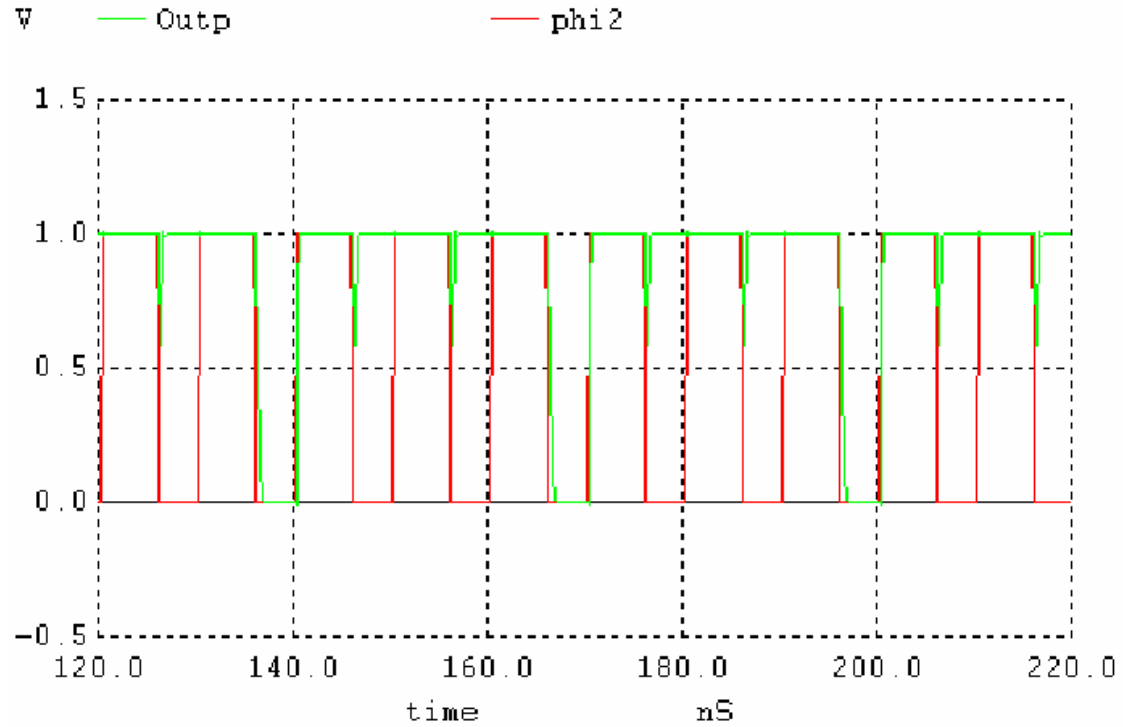
## Operation :

When  $\phi_2 = 1$ , Two upper PMOS transistor will be ON and M5 and M6 will be off, NMOS M3 and M4 has gate at VDD and M1 and M2 has gate at Bit line and VDD/2. Since there is no current in this case because M5 and M6 are off so X1 and Y1 are pulled to gnd.. Both the outputs will be high in this case.

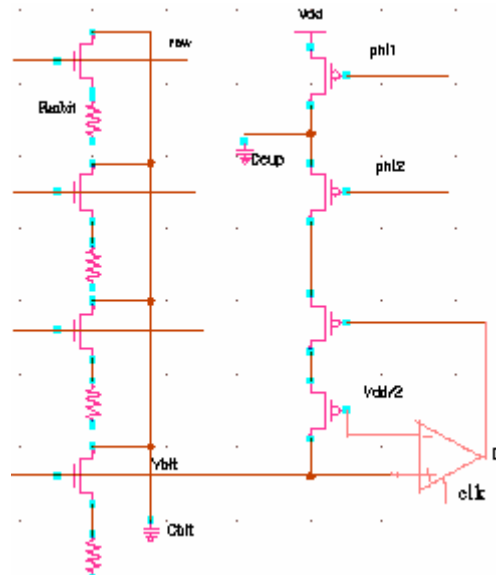
When  $\phi_2 = 0$ , Sensing operation starts, both outputs are pulled towards low (initially), but at different rates, If bitline  $< V_{DD}/2 + V_{OS}$  then Output Y will go to gnd finally and X will be at VDD and if bitline  $>$

$V_{DD}/2 + V_{os}$  then output Y will be at  $V_{DD}$  but it will glitch ( because initially both the outputs are pulled towards gnd).

This glitch may cause Error in Averaging , because when we expect there is no charge transfer from  $C_{cup}$  to  $C_{bit}$  , It can transfer the charge because of the glitch. The simulation below shows the glitch vs. time.



17.8) The following equations and values were chosen for designing DSM circuit that determines the value of resistor that ranges from 100k to 10 M $\Omega$ .



First, the value of  $C_{cup}$  was found by using following equation:

$$C_{cup} = \frac{V_{os.T}}{((V_{dd}-V_{thp}) * M/N * R_{bit})}$$

The Vos value picked as a nominal value of 0.05 V, Vthp= 280 mV and f and where Rbit is picked as 50k.

By assuming frequency to be 100MHz, we get  $C_{cup}$  to be 90 fF since the offset varies with process, the capacitor is used as 100fF.

Now  $R_{\text{bit}} = 25k * N/M$

The simulation was done by using Ccup less than Cbit(500fF) and using 100k and 10M for Rmbit. The following Rmbit was found by using total clock pulses divided by those clock pulses that go high. The simulation results are shown below. By clocking 100 MHz for 4 us, we get 400 clock pulses.

From sim figure 1

Rmbit = 25k. 400/80 = 125k (the actual value being 100k)

From sim fig 2

$$R_{\text{mbit}} = 25\text{k} \cdot 400/1 = 10\text{M}$$



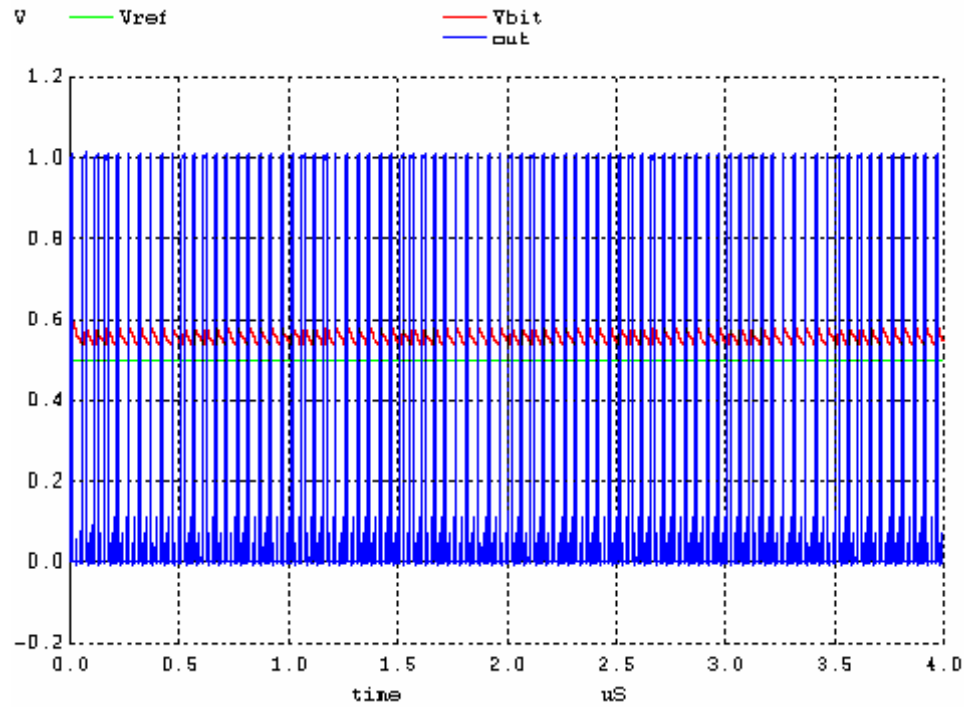


Fig1: For  $R_{mbit} = 100K$

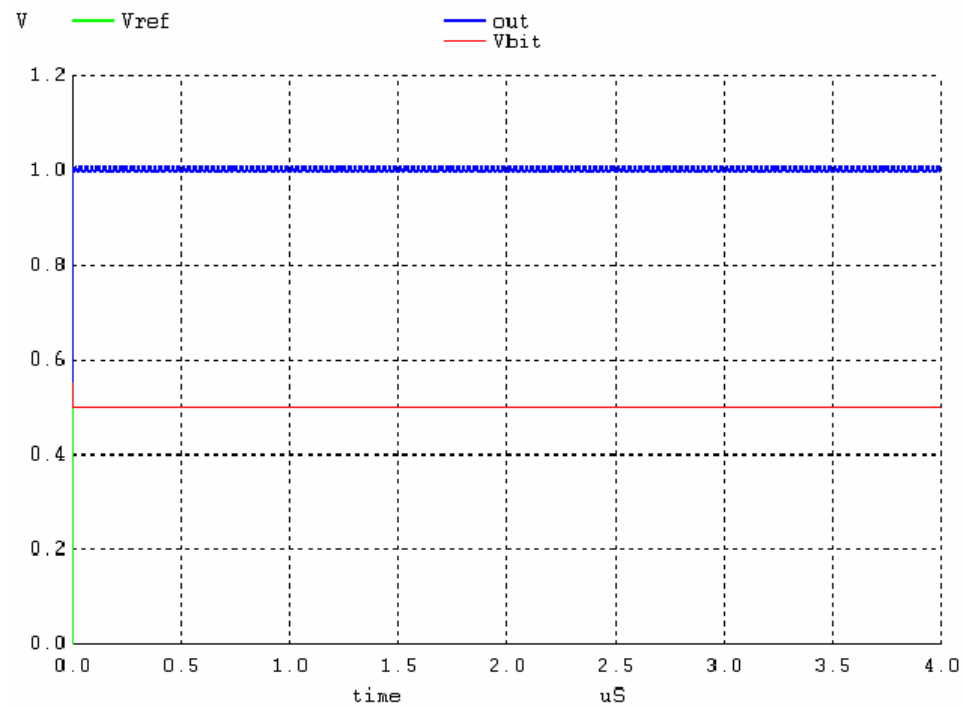


Fig2: For  $R_{mbit} = 10M$

There will be process variation regarding from the offset voltage and resistance within the MOSFET and threshold voltages that will affect the results. These parameters will affect  $C_{cup}$  since  $C_{bit}$  is always

constant. It will change the clock high pulses (M) thus ultimately giving out the different result. The frequency will also affect the value of Ccup thus changing Rmbit.

### Problem 17.9

**Suppose, that it is desired to have a noise floor of  $100\mu V$  RMS in a CMOS imager. Further suppose the sensing circuit doesn't contribute any noise to the sense (the transformation from the analog column voltage to the digital word). Estimate the size of the hold capacitors used to sample both the reference and intensity signals.**

**Solution:** Referring to Equation 8.24 which is the expression for the RMS noise voltage through a capacitor, famously called the “Kay tee over cee” noise:

$$V_{RMS,noise} = \sqrt{\frac{k \cdot T}{C}}$$

where

k = Boltzmann's constant =  $1.38 \cdot 10^{-23}$  J/K

T = Temperature in Kelvin = 300 K

C = Capacitance in Farads

$$100\mu V = \sqrt{\frac{1.38 \cdot 10^{-23} \cdot 300}{C}}$$

$$\therefore C = 414 fF$$

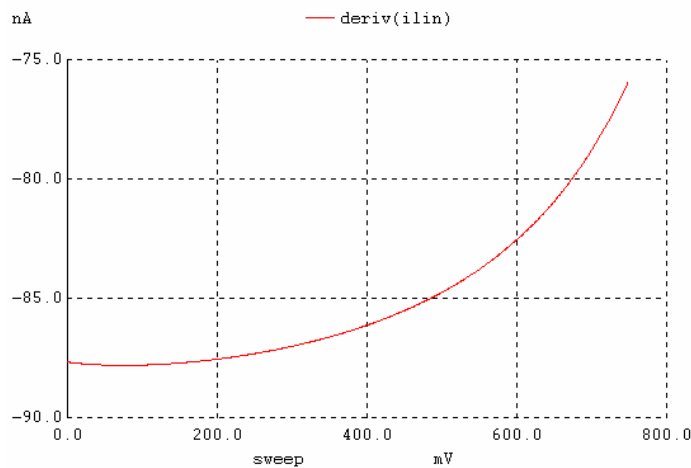
So the size of the hold capacitors that can be allowed for a noise floor of  $100\mu V$  in the imager is  $414 fF$ .

## 17.10 - Solution by Eric Booth

Using simulations determine if the linearity of the voltage-to-current converter can be made better by adjusting the length of the PMOS device seen in Fig 17.28. Why does, or doesn't, the performance get better?

In order to gather data for this problem, I plotted the derivative of the transfer curve of the device using different L & W values. One way of quantifying the linearity is to divide the change in  $dI/dV$  by the ideal value of  $-100\text{nA/V}$ .

For example, the plot below was created with a device of  $L=1$  and  $W=5$ . The change in  $dI/dV$  over the full range is  $\sim 12\text{nA/V}$  or 12%. The linearity is best from 0V to 400mV, so it would be useful to quantify this value as well. For this device it is  $\sim 2\%$

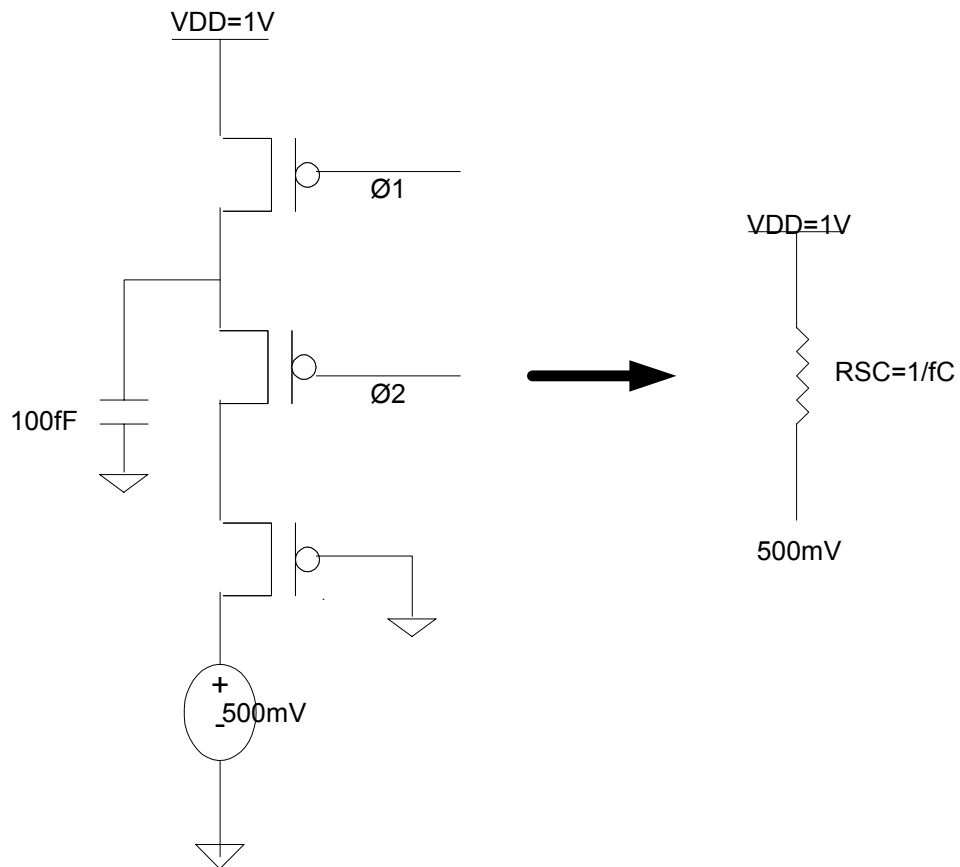


Using this method,

W/L	Linearity (full range)	Linearity (<400mV)
2/1	14%	2%
5/1	12%	2%
10/1	10%	1.5%
20/1	8.5%	1.2%
50/1	7%	1.5%
100/1	6%	3%
20/2	15%	2.5%
20/5	14%	2.5%
20/10	15%	3%
20/20	17%	3%
20/50	20%	4%
20/100	25%	5%

From the table, we can see that as a general rule, increasing W or decreasing L increases the linearity. This is because the linearity of this system requires that the  $V_{gs}$  of the device is a constant, however  $I_d$  and  $V_{ds}$  are changing. A larger  $\beta$  factor ensures that the device will be able to source different currents at different  $V_{ds}$  with smaller changes in  $V_{gs}$ .

### 17.11 Solution



The current that flows through the Resistor  $R_{SC}$  is

$$I_{avg} = (VDD - 0.5) / R_{sc}$$

Where  $R_s = 1/fC$  where  $f = 100\text{Mhz}$  and  $C = 100\text{fF}$

Therefore  $R_{sc} = 100\text{K ohms}$

Therefore  $I_{avg} = 0.5 / 100\text{K} = 5\text{u amps}$

\*\*\* Problem 17.11 CMOS: Circuit Design, Layout, and Simulation \*\*\*

```
.control
destroy all
run
plot phil phi2+1.25 xlimit 100n 150n
plot Vbit#branch xlimit 15n 20n
plot Vbit#branch
print mean(-vdd#branch)
```

```
.endc
```

```
.option scale=50n
```

```
.tran 100p 500n 10n 100p
```

```
VDD    VDD    0      DC    1
Vphil  phil   0      DC    0      PULSE 1 0 1n 0 0 4n 10n
```

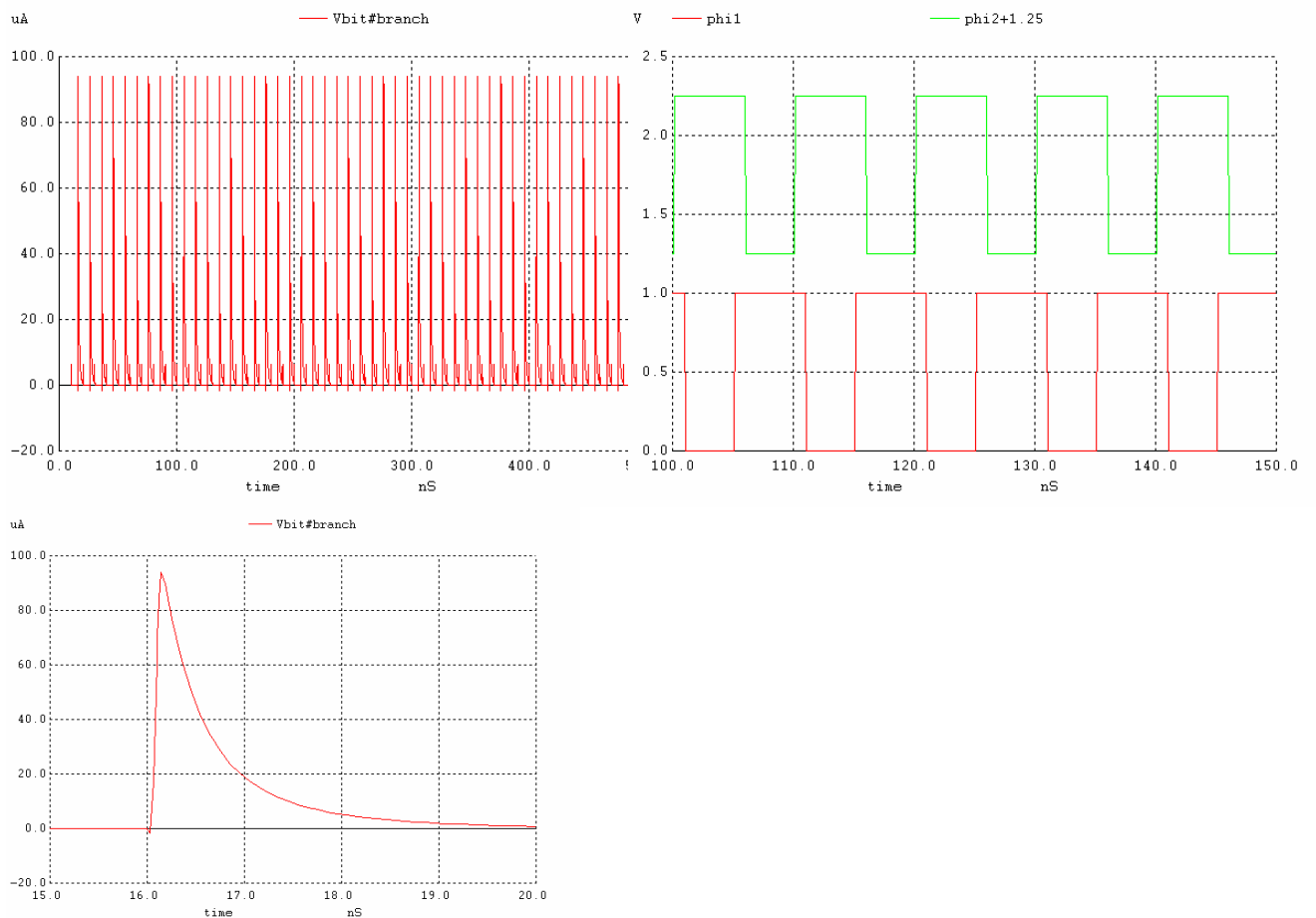
```

Vphi2 phi2 0 DC 0 PULSE 1 0 6n 0 0 4n 10n
*Add resistors to the sim just to make sure the voltage sources always
have a load.
*Rphil phi1 0 1G
*Rphi2 phi2 0 1G
Vbit Vbit 0 DC 0.5

M1 Vd1 phi1 VDD VDD PMOS L=1 W=20
M2 Vd2 phi2 Vd1 vdd PMOS L=1 W=20
M3 Vbit 0 Vd2 Vdd PMOS L=1 W=20
Ccup Vd1 0 100f

```

Simulation Results  
Transient analysis ... 100%  
mean(-vdd#branch) = 9.013932e-06



### Problem 17.12

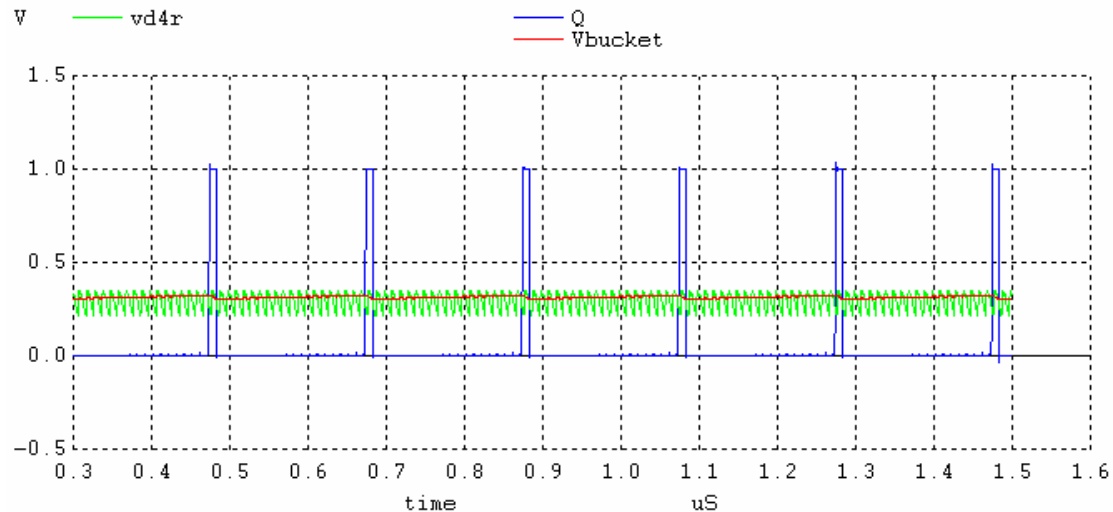
What happens to the simulation results seen in Fig. 17.34, if the time step used in the transient simulation is increased to 1ns? How do the nonoverlapping clocks look with this time step?

Lets focus this solution on the results of Figure 17.34(b).

$V_R = 650 \text{ mV}$

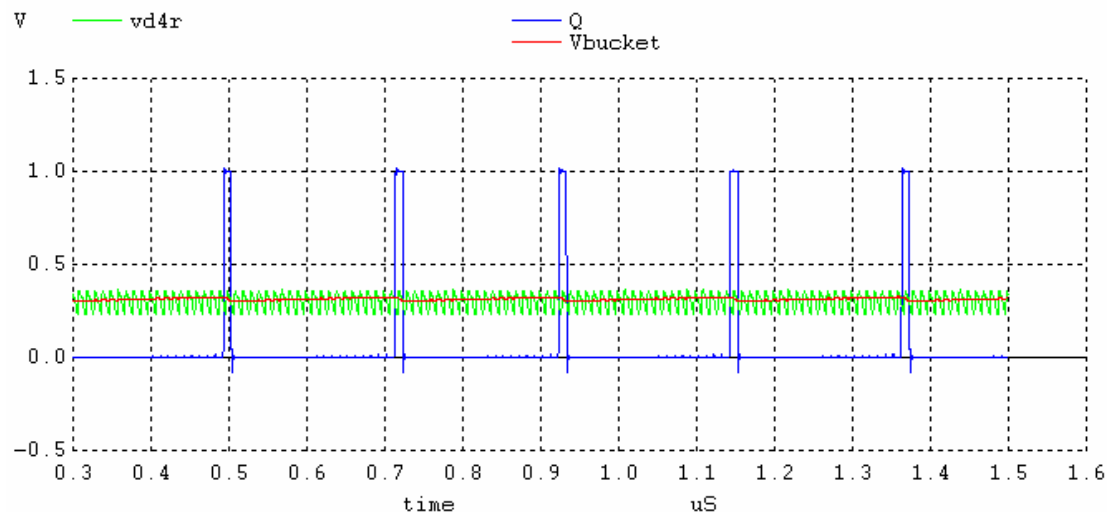
$V_I = 645 \text{ mV}$

In Figure 17.34(b) the time step is 0.5ns. This results in the following plot of Q vs time;

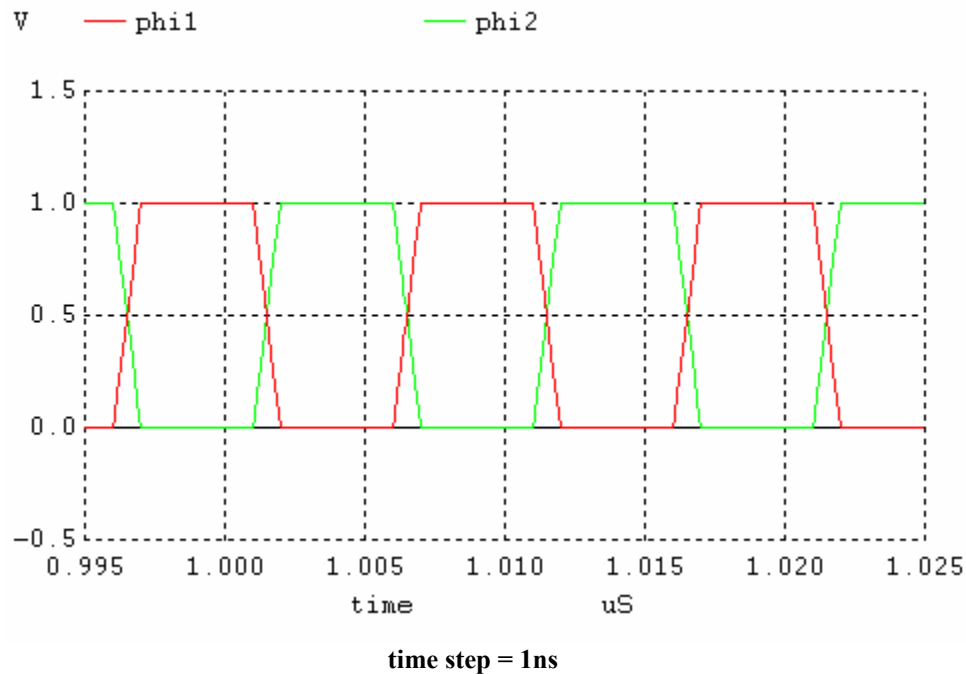
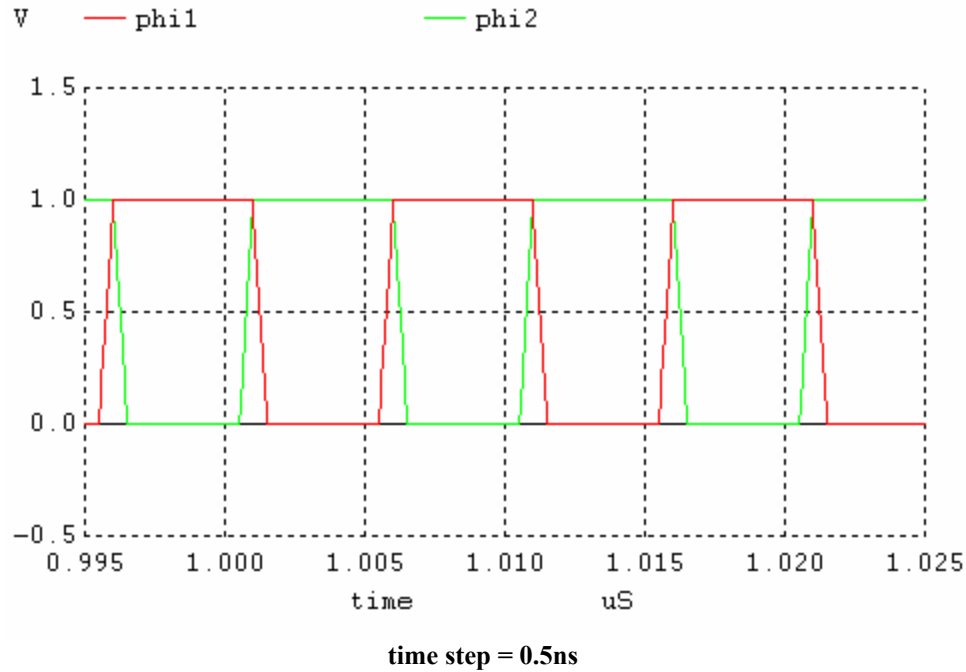


Examining the plot above, we see that Q goes high 5 times while the counter is enabled (0.5 $\mu\text{s}$  to 1.5 $\mu\text{s}$ )

Now if we increase the simulation time step from .5ns to 1ns we get the following plot of Q vs time.



Examining the plot above we see that when the counter is enabled Q goes high 4 times, although when the counter is first enabled, Q is high so depending on the counter the result may be Q high five times. The main point is that Q is going high less frequently. To better understand this, lets take a look at what is happening to the nonoverlapping clocks when the simulation time step is increased (.5ns to 1ns)



The two plots above show a zoomed in view of **phi1** and **phi2**. In both plots the time period is 10ns with the signal high for 4 ns. The difference between the plots is the rise and fall times of the signals. The rise and fall times default to the simulation time step. So in the top plot we have a rise time = fall time = .5ns. Subtracting the total time period(10ns) by the time high(4ns) and the combined rise and fall times(1ns) leaves 5 ns for the signals to be low. In the second plot we have a rise time = fall time = 1ns. This leaves only 4ns for the signal to be low(10ns-4ns-1ns-1ns).

If we look back at Figure 17.33 we see that **phi1** and **phi2** control the switched capacitors via pmos transistors. Since **phi1** and **phi2** are low for a less amount of time with the higher time step, less charge will be able to go to the  $C_{cup}$  capacitors. This essentially will increase the  $R_{SC}$  for each side, which will lower the current that flows through each side.

With a lower current flowing through both sides it takes longer to drain the charge on  $C_{bucket}$ . . Yes its true that the charge on  $C_{cup}$  is also less but in this case the lower current affects the results more than the smaller  $C_{cup}$  charge.



### Problem 17.13

Figure 1 shows the outputs of the comparator from figure 17.44. As can be seen, the outputs of the comparator do not make full logic levels. They will reach VDD but not 0.

The glitches seen in Figure, will cause switches to turn on, (when they aren't supposed to,) and inadvertently dump some charge. This will affect the resolution of the sense.

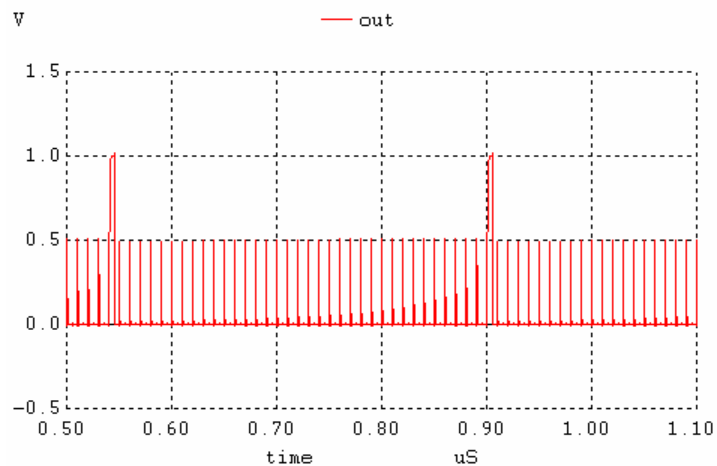


Figure 1.

Adding inverters to the output of the comparator cleans up these glitches (figure 2.). Notice in the netlist, (at the end of this solution,) that the size of the inverter MOSFETS have been adjusted to move the switching point of the inverters to help eliminate the glitches.

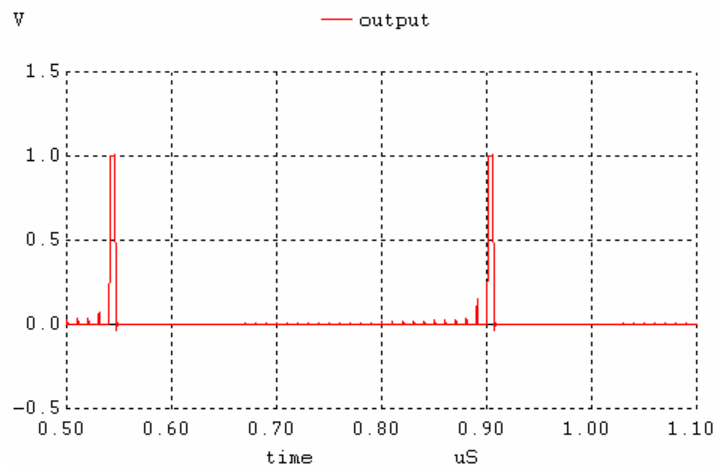


Figure 2.

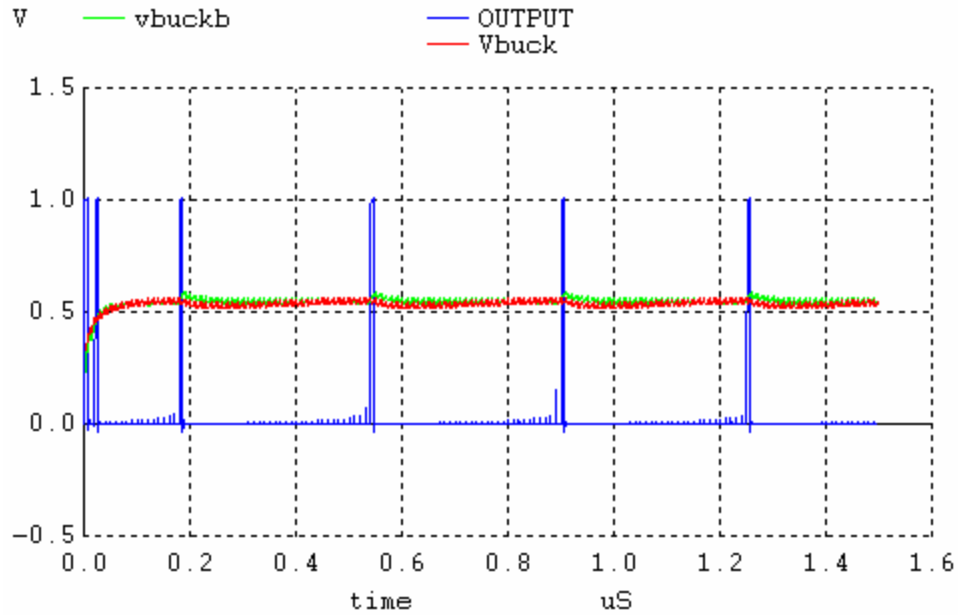


Figure 17.37a.

The simulation results for figure 17.37a, above show it's comparator making full logic levels, this is because of the SR latch on the outputs it's comparator.

Comparing figures 17.37a through e with figures 17.44a through e, below, we see that:

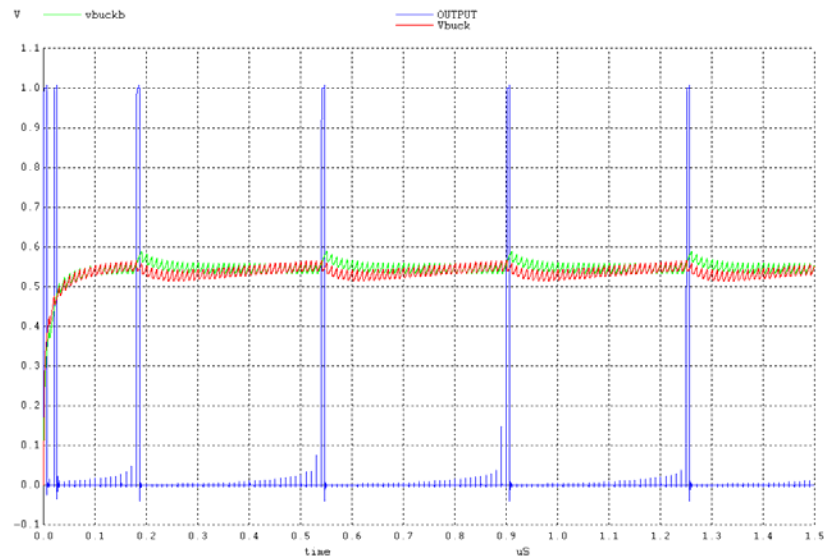


Figure 17.44a

$V_{\text{shift}} = 640\text{mV} - 215\text{mV} = 425\text{mV}$ , and the sensed value is  $435\text{mV} \times 94/100 = 418\text{mV}$ . This is compared to  $426\text{mV}$  sensed in figure 17.37a.

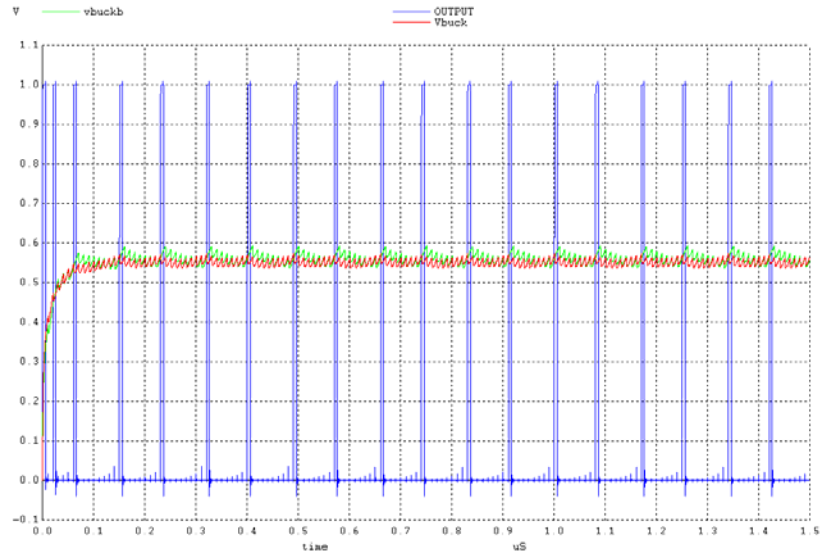


Figure 17.44b

$V_{shift} = 600\text{mV} - 215\text{mV} = 385\text{mV}$ , and the sensed value is  $435\text{mV} \cdot 89/100 = 387\text{mV}$ .  
Compared to  $382\text{mV}$  in figure 17.37b.

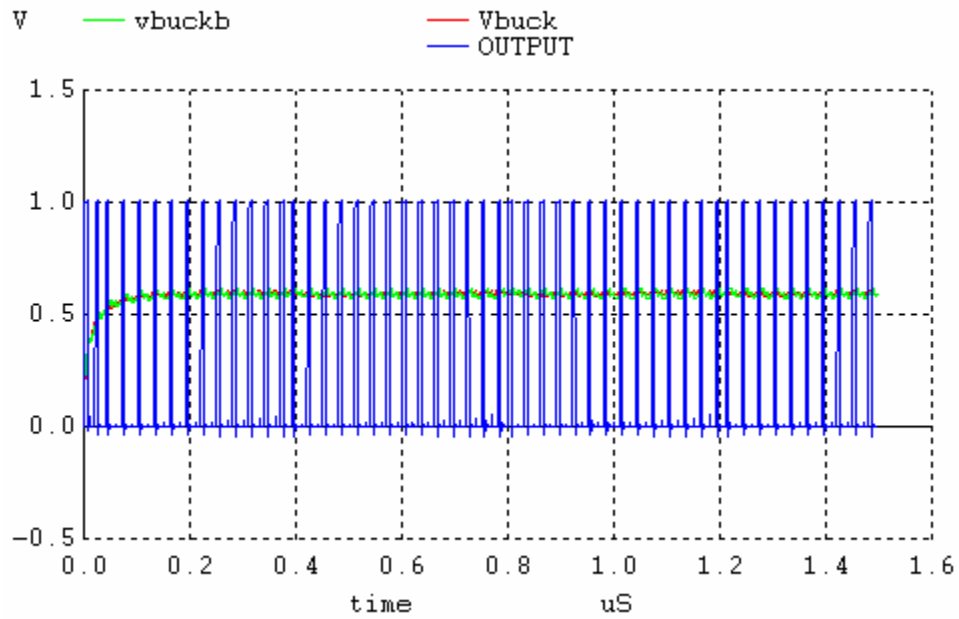


Figure 17.44c

$V_{shift} = 500\text{mV} - 215\text{mV} = 285\text{mV}$ , and the sensed value is  $435\text{mV} \cdot 66/100 = 287\text{mV}$ . Compared with  $283\text{mV}$ .

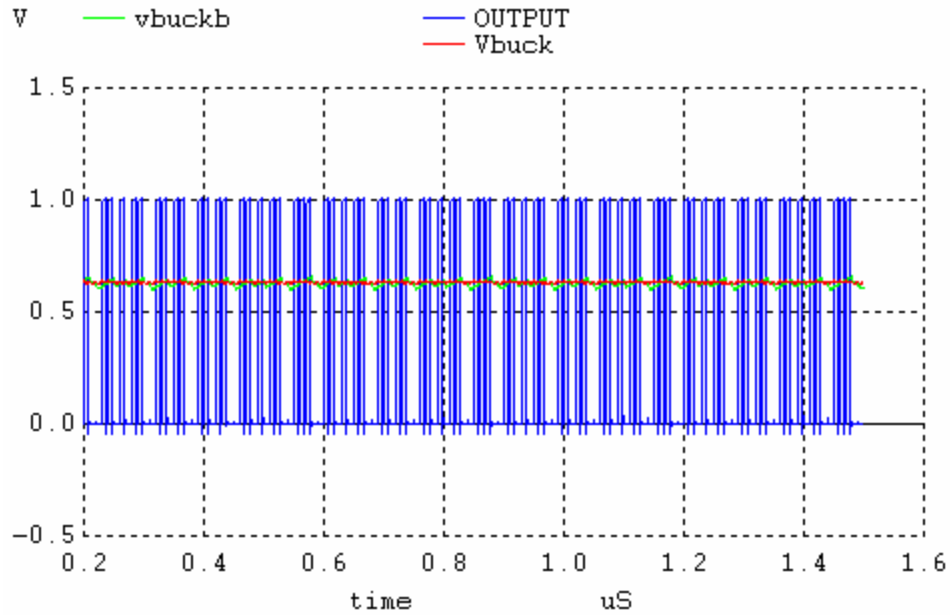


Figure 17.44d

$V_{shift} = 400\text{mV} - 215\text{mV} = 185\text{mV}$ , and the sensed value is  $435\text{mV} \cdot 44/100 = 191\text{mV}$ . This is compared to a value of 191mV in figure 17.37d.

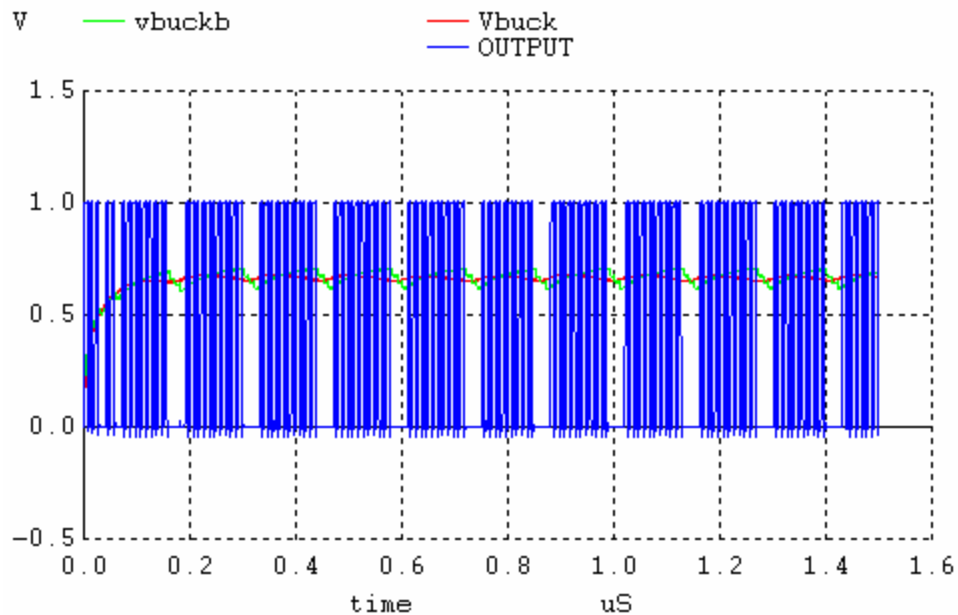


Figure 17.44e

$V_{shift} = 300\text{mV} - 215\text{mV} = 85\text{mV}$ , and the sensed value is  $435\text{mV} \cdot 22/100 = 96\text{mV}$ . This is compared to a value of 104 mV.

As can be seen from the figures above, the fact that the comparator doesn't make full logic levels, indicates that our resolution will be off.

```
.control
destroy all
run
plot Vbuck vbuckb OUTPUT
.endc
```

```
.option scale=50n
.tran .25n 1500n 0 .25n UIC
```

VDD	VDD	0	DC	1	
Vphi1	phi1	0	DC	0	PULSE 0 1 1n 0 0 4n 10n
Vphi2	phi2	0	DC	0	PULSE 0 1 6n 0 0 4n 10n

Vblack	Vr	0	DC	650mV
Vinten	Vi	0	DC	300mV

M1r	Vbuckb	vr	vdr2	0	NMOS L=1 W=10
M2r	Vdr2	OUTB	vdr3	0	NMOS L=1 W=10
M3r	Vdr3	phi1	vdr4	0	NMOS L=1 W=10
M4r	Vdr4	phi2	0	0	NMOS L=1 W=10
Mcupr	VDD	vdr4	VDD	VDD	PMOS L=10 W=50

M1i	Vbuck	vi	vdi2	0	NMOS L=1 W=10
M2i	Vdi2	VDD	vdi3	0	NMOS L=1 W=10
M3i	Vdi3	phi1	vdi4	0	NMOS L=1 W=10
M4i	Vdi4	phi2	0	0	NMOS L=1 W=10
Mcupi	VDD	Vdi4	VDD	VDD	PMOS L=10 W=50

M1p	vbuckb	vbuckb	VDD	VDD	PMOS L=10 W=10
M2p	vbuck	Vbuckb	VDD	VDD	PMOS L=10 W=10
Mbuck	0	Vbuck	0	0	NMOS L=10 W=500
Mbuckb	0	Vbuckb	0	0	NMOS L=10 W=500

MCP1	vp1	Vbuck	VDD	VDD	PMOS L=1 W=20
MCP2	vp2	out	vp1	VDD	PMOS L=1 W=20
MCP3	outb	phi2	vp2	VDD	PMOS L=1 W=20
MCP4	vp3	Vbuckb	VDD	VDD	PMOS L=1 W=20
MCP5	vp4	outb	vp3	VDD	PMOS L=1 W=20
MCP6	out	phi2	vp4	VDD	PMOS L=1 W=20

MCN1	outb	phi2	0	0	NMOS L=1 W=10
MCN2	outb	out	0	0	NMOS L=1 W=10
MCN3	out	outb	0	0	NMOS L=1 W=10
MCN4	out	phi2	0	0	NMOS L=1 W=10

```
MINV1 OUT1_OUT VDD VDD PMOS L=1 W=2
MINV2 OUT1_OUT 0 0 NMOS L=1 W=4
MINV3 OUTPUT OUT1_VDD VDD PMOS L=1 W=2
MINV4 OUTPUT OUT1_0 0 NMOS L=1 W=4
```

\* BSIM4 models